

Characterisation of Materials at FACTS



Dr. Chris Boothroyd

南洋理工大学
Nanyang Technological University,
Singapore
Principal Research Fellow
Expertise: Advanced TEM, STEM and
analysis

The facility for analysis, characterisation, testing and simulation (FACTS) hosts scanning electron microscopes, transmission electron microscopes and X-ray diffraction equipment supported by dedicated instrument scientists and is open to all users at NTU. It is open to scientists who are conducting cutting edge research and caters for both expert and casual users. Our scientists also conduct independent research and collaborate with scientists in NTU, other Singapore universities and with researchers abroad.

Our equipment has been used to understand the properties of materials ranging from aerospace alloys to biomaterials, rocks, polymers, quasicrystals and magnetic materials. In this seminar I will give a flavour of some of the many materials analysed by scientists at FACTS and talk about some of the work I have been involved in on cold sprayed alloys and phase-shifting electron holography.

2019(令和元)年

6月6日(木)

1:30pm~2:30pm

(開場 1:00pm)

Doors open

会場 Venue:

千現地区 第2会議室

The 2nd conference room, Sengen site, NIMS

言語 Language:

英語 English

※講義は英語で行います。1:20 pm までにご入室をお願い致します。

You are kindly asked to enter the conference room before 1:20p.m.

申込方法 How to Apply:

参加ご希望の方はインターネットのフォームよりお申し込みください。締め切り後は直接会場にお越しください。

※当日受付にてお名前の記入をお願いします。

Please apply from the internet form.

Please come directly to the venue after the deadline.

※You will be asked to write your name on a sheet before the seminar.

Pre-registration Deadline : 6/5 noon

事前登録〆切 : 6/5 正午

入場無料
Admission Free

Application



QR code

NIMS電子顕微鏡ステーション事務局 Email: tem@nims.go.jp Tel: 029-859-2150

インターネットからのお申込み ▶ https://www.nims.go.jp/tem/news/20190606_001.html